

Supporting information for

Kinetics of irreversible chain adsorption

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A series of films whose thickness covered the entire investigated range was analyzed also via atomic force microscopy. We scratched the surface of the films with a soft pen that removed the organic layer without damaging the inorganic substrate, see Figure 1. We obtained topography images in tapping mode, to avoid any impact of the AFM tip on the polymer surface.

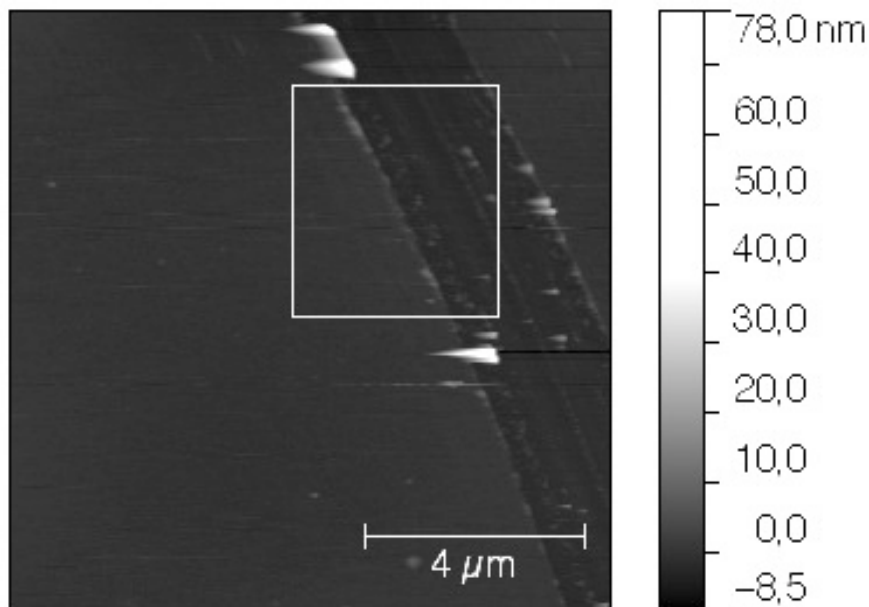


Figure S1

The thickness of the polymer layer was determined considering the distribution of distances plane parallel to the surface, placed at an arbitrary quota, see sketch in Figure S2 and Figure S3. The difference between the maxima in the two peaks (indicating the distribution of distance between the measuring plane and the substrate and between the measuring plane and the polymer surface) provided the mean value of the thickness of the film.

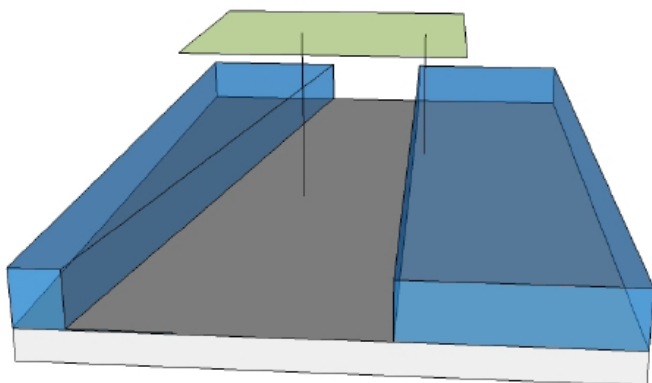


Figure S2

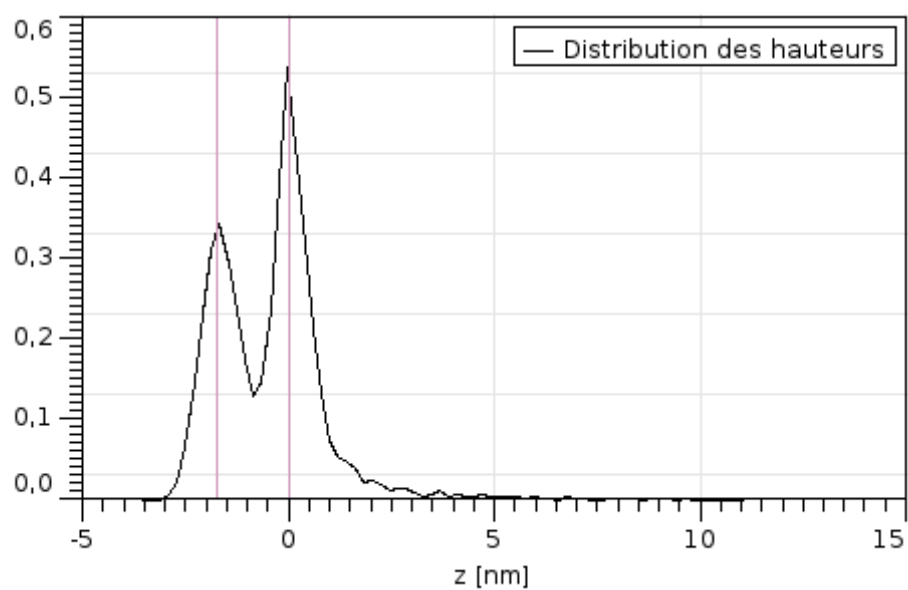


Figure S3

Further fitting results

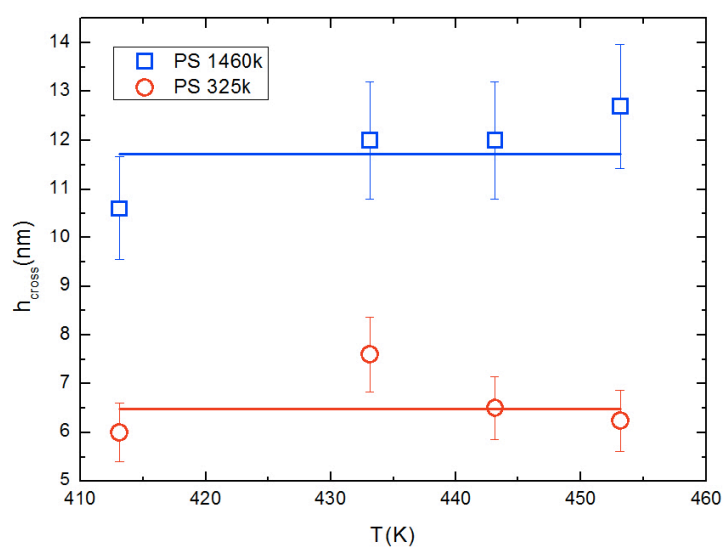


Figure S4 Lack of temperature dependence for h_{cross} .

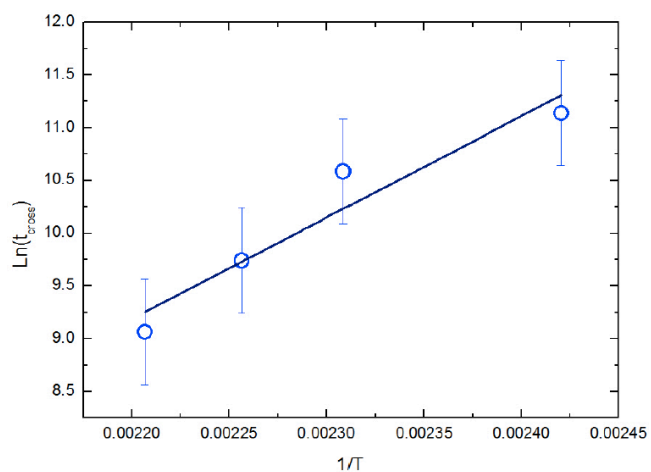


Figure S5 Activation plot for the crossover time.

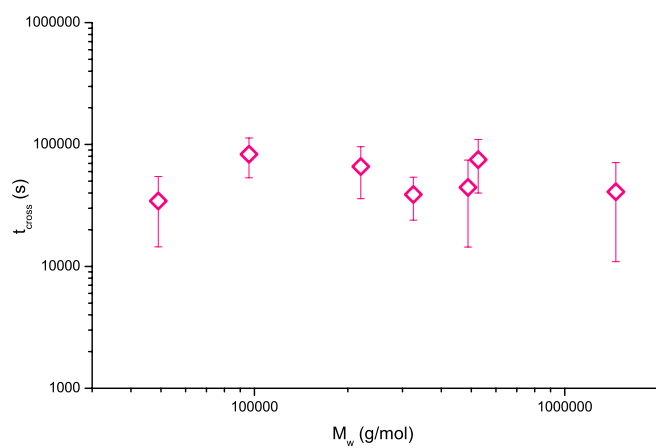


Figure S6 Molecular weight dependence of the crossover time.